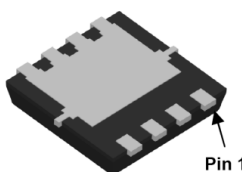
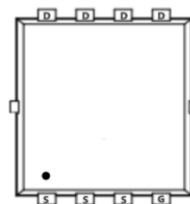


Main Product Characteristics:

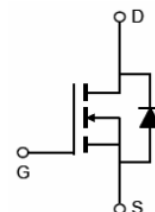
V_{DSS}	30V
$R_{DS(on)}$	3.5m Ω (typ.)
I_D	70A



PDFN 3*3-8L



Pin Assignment



Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I_D @ $T_C = 25^\circ\text{C}$	Continuous Drain Current, V_{GS} @ 10V ①	70	A
I_{DM}	Pulsed Drain Current ②	160	
P_D @ $T_C = 25^\circ\text{C}$	Power Dissipation ③	59	W
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy @L=0.1mH	115.2	mJ
I_{AS}	Avalanche Current @L=0.1mH	48	A
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

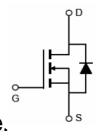
Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	2.1	$^{\circ}C/W$
$R_{\theta JA}$	Junction-to-ambient ($t \leq 10s$) ④	—	62	$^{\circ}C/W$

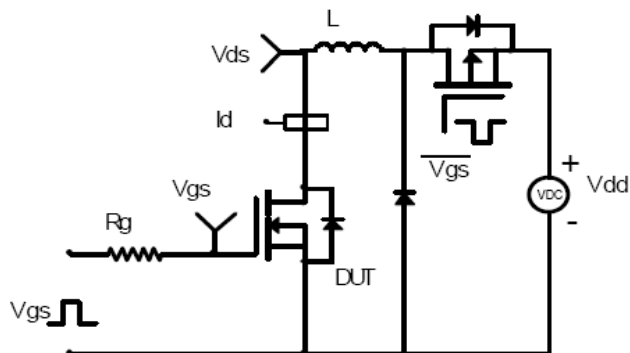
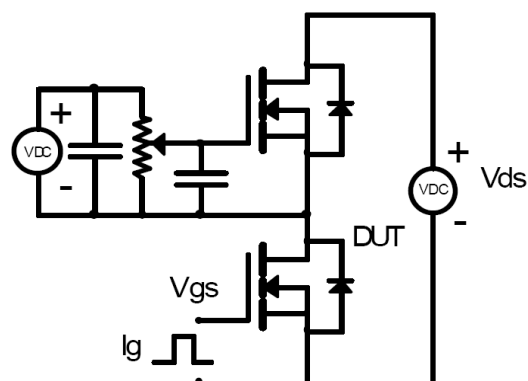
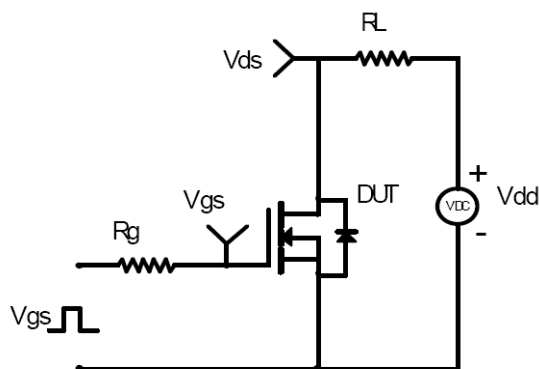
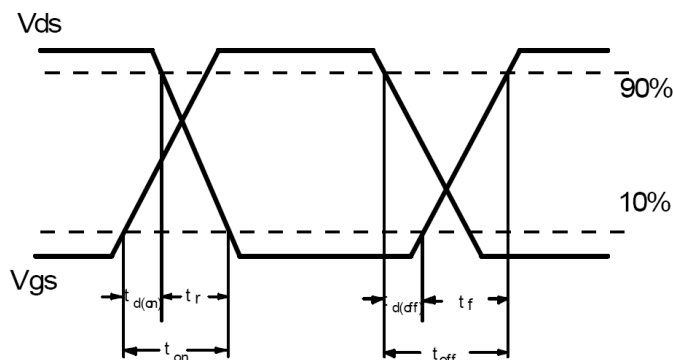
Electrical Characterizes @ $T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	3.5	5.5	m Ω	$V_{GS}=10V, I_D=30A$
		—	6.5	8.5		$V_{GS}=4.5V, I_D=15A$
$V_{GS(th)}$	Gate threshold voltage	1	—	2.5	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
I_{DSS}	Drain-to-Source leakage current	—	—	1	μA	$V_{DS} = 24V, V_{GS} = 0V$
I_{GSS}	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20V$
		—	—	-100		$V_{GS} = -20V$
Q_g	Total gate charge	—	19.5	—	nC	$I_D = 15A,$ $V_{DS}=15V,$ $V_{GS} = 4.5V$
Q_{GS}	Gate-to-Source charge	—	7.5	—		
Q_{gd}	Gate-to-Drain("Miller") charge	—	7.1	—		
$t_{d(on)}$	Turn-on delay time	—	7.5	—	ns	$V_{GS}=10V, V_{DS}=15V,$ $R_{GEN}=3.3\Omega$ $I_D = 15A$
t_r	Rise time	—	14.8	—		
$t_{d(off)}$	Turn-Off delay time	—	37.1	—		
t_f	Fall time	—	10.4	—		
C_{iss}	Input capacitance	—	2290	—	pF	$V_{GS} = 0V$ $V_{DS} = 15V$ $f = 1MHz$
C_{oss}	Output capacitance	—	265	—		
C_{riss}	Reverse transfer capacitance	—	209	—		

Source-Drain Ratings and Characteristics

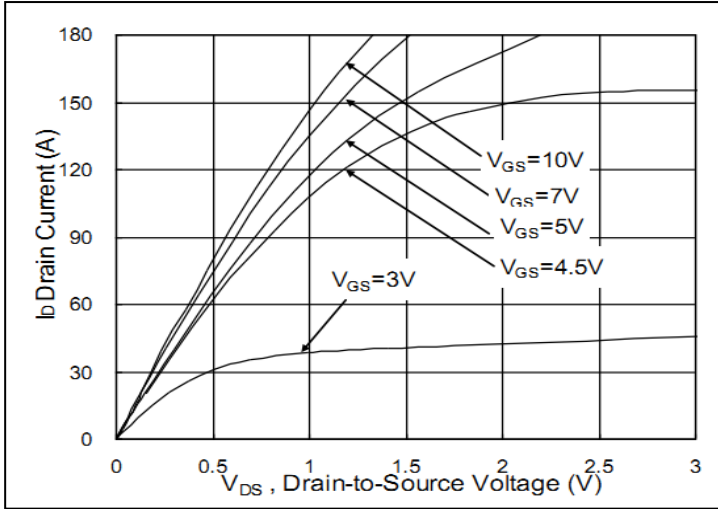
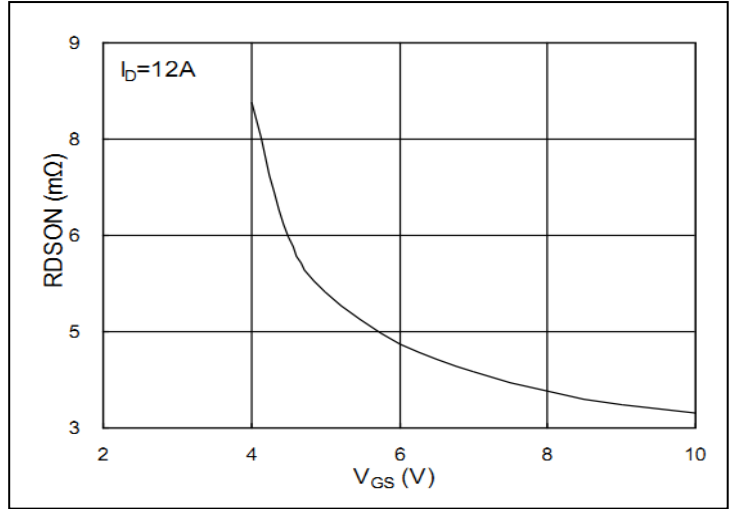
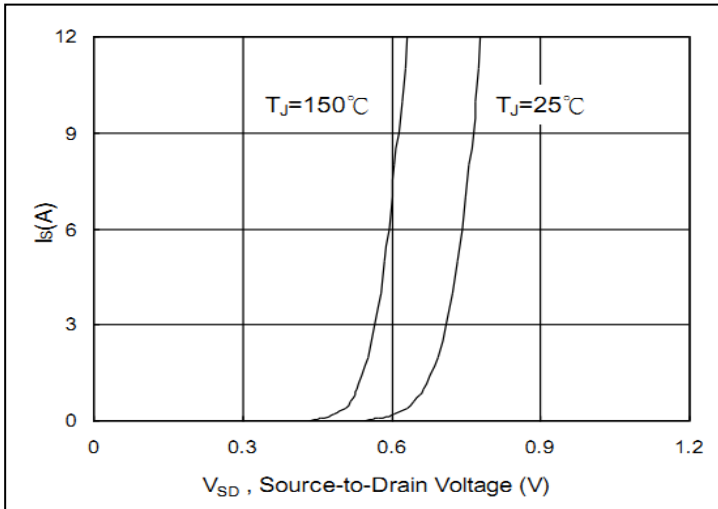
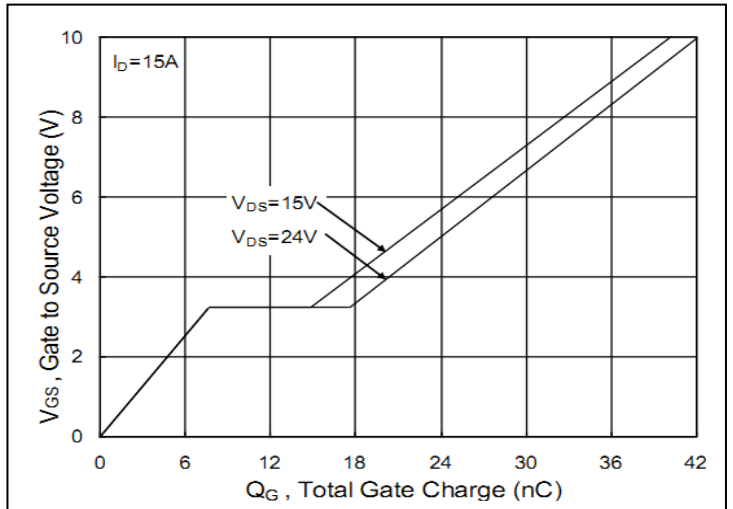
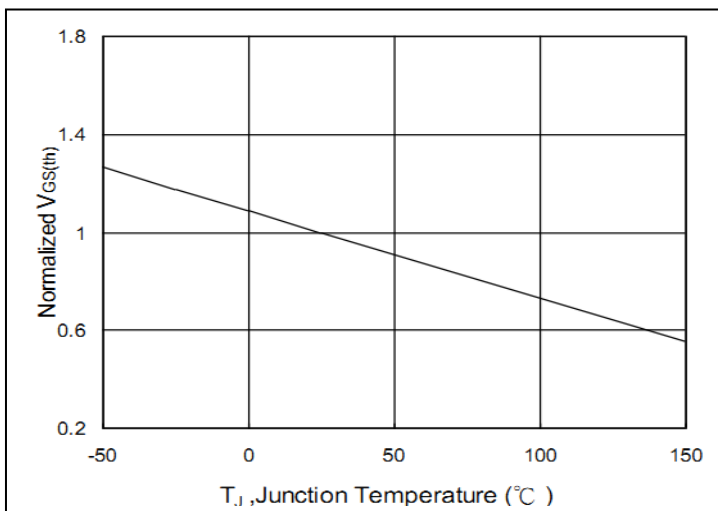
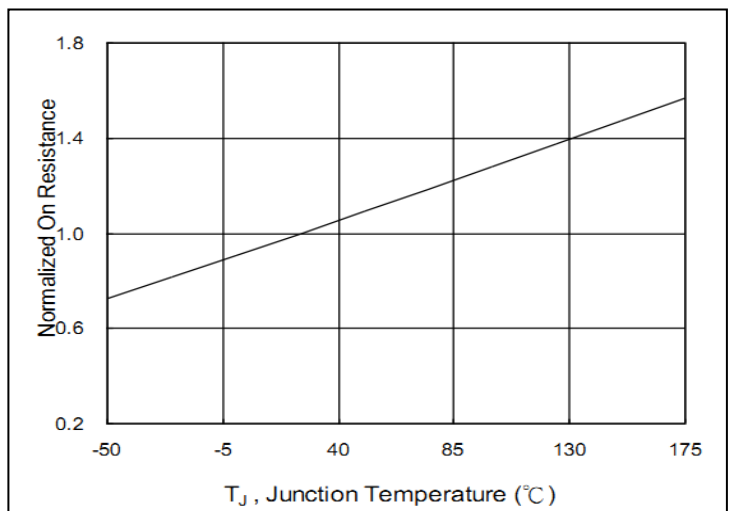
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	80	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode)	—	—	160	A	
V_{SD}	Diode Forward Voltage	—	—	1	V	$I_S=1A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	—	14	—	nS	$T_J = 25^{\circ}C, I_F = 30A,$ $di/dt = 100A/\mu s$
Q_{rr}	Reverse Recovery Charge	—	5	—	nC	

Test circuits and Waveforms

EAS Test Circuit:

Gate charge test circuit:

Switching Time Test Circuit:

Switching Waveforms:


Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$

Typical electrical and thermal characteristics

Figure 1: Typical Output Characteristics

Figure 2: On-Resistance vs. G-S Voltage

Figure 3: Forward Characteristics of Reverse

Figure 4: Gate Charge

Figure 5: Normalized $V_{GS(th)}$ vs. Case Temperature

Figure 6: Normalized On-Resistance vs. Case Temperature

Typical electrical and thermal characteristics

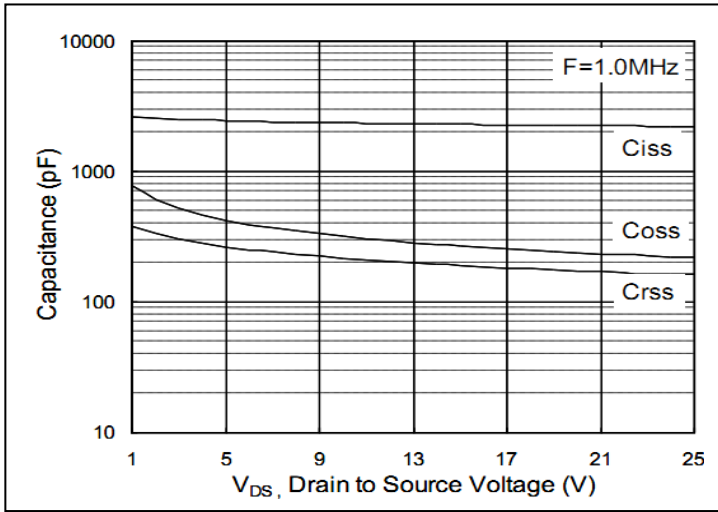


Figure 7: Capacitance

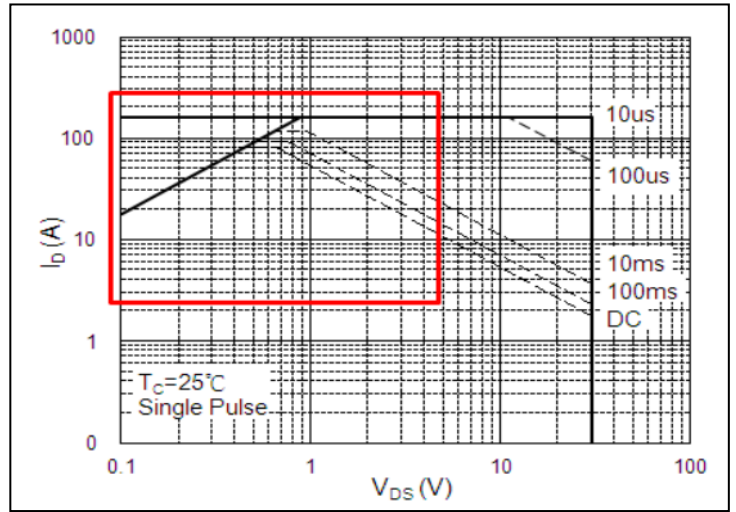


Figure 8: Safe Operation Area

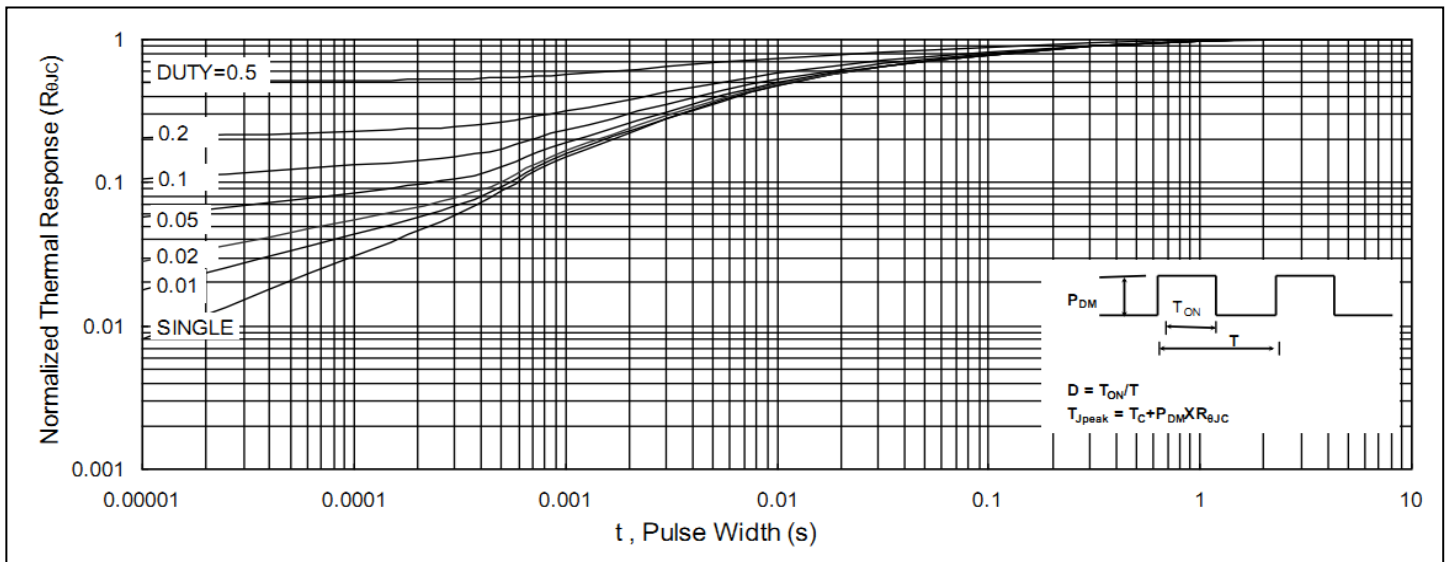
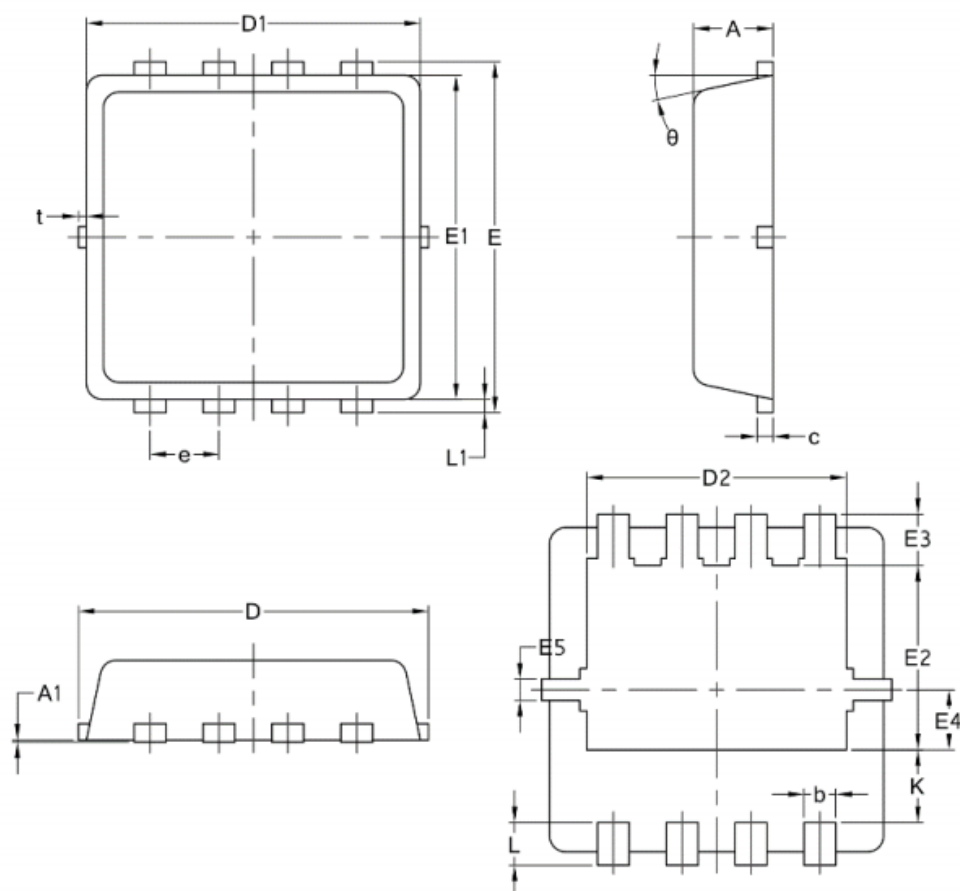


Figure 9: Transient Thermal Impedance

Mechanical Data:


Symbol	Common		
	mm		
	Mim	Nom	Max
A	0.70	0.75	0.85
A1	/	/	0.05
b	0.20	0.30	0.40
c	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
e	0.60	0.65	0.70
K	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
Φ	10	12	14

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